

OptiMOS[™]2 Small-Signal-Transistor

Features

- N-channel
- Enhancement mode
- Ultra Logic level (1.8V rated)
- · Avalanche rated
- Qualified according to AEC Q101
- 100% lead-free; RoHS compliant
- Halogen-free according to IEC61249-2-21

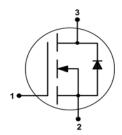




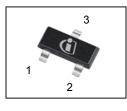


Product Summary

V _{DS}	20	V	
$R_{\rm DS(on),max}$ $V_{\rm GS}$ =2.5 V		57	mΩ
	V _{GS} =1.8 V	82	
I _D	2.3	Α	



PG-SOT23



Туре	Package	Tape and Reel Information	Marking	Lead Free	Packing
BSS806N	SOT23	H6327: 3000 pcs/ reel	YEs	Yes	Non dry

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _A =25 °C	2.3	А
		T _A =70 °C	1.9	
Pulsed drain current	I _{D,pulse}	T _A =25 °C	9.3	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =2.3 A, $R_{\rm GS}$ =25 Ω	10.8	mJ
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =2.3 A, $V_{\rm DS}$ =16 V, d <i>i</i> /d <i>t</i> =200 A/ μ s, $T_{\rm j,max}$ =150 °C	6	kV/μs
Gate source voltage	V_{GS}		±8	V
Power dissipation ¹⁾	P_{tot}	T _A =25 °C	0.5	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55 150	°C
ESD Class		JESD22-A114 -HBM	0(<250V)	
Soldering Temperature			260 °C	
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - ambient	$R_{ m thJA}$	minimal footprint 1)	-	-	250	K/W

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 250 μA	20	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _D =11 μA	0.3	0.55	0.75	
Drain-source leakage current	I _{DSS}	$V_{\rm DS}$ =20 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	1	1	μΑ
		V _{DS} =20 V, V _{GS} =0 V, T _j =150 °C	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =8 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =1.8 V, I _D =1.3 A	-	57	82	mΩ
		V _{GS} =2.5 V, I _D =2.3 A	1	41	57	
Transconductance	$g_{ ext{fs}}$	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 1.9 \text{ A}$		9	-	S

 $^{^{1)}}$ Performed on 40mm^2 FR4 PCB. The traces are 1mm wide, $70\mu\text{m}$ thick and 20mm long; they are present on both sides of the PCB.



Parameter	Symbol	Symbol Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	370	529	pF
Output capacitance	Coss	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =10 V, f=1 MHz	-	118	169	
Reverse transfer capacitance	C _{rss}] [-	20	29	
Turn-on delay time	t _{d(on)}		-	7.5	-	ns
Rise time	t _r	V _{DD} =10 V, V _{GS} =2.5 V,	-	9.9	-	
Turn-off delay time	$t_{\text{d(off)}}$	$I_{\rm D}$ =2.3A, $R_{\rm G}$ =6 Ω	-	12.0	-	
Fall time	t_{f}] [-	3.7	-	
Gate Charge Characteristics				_		
Gate to source charge	Q _{gs}	$V_{\rm DD}$ =10 V, $I_{\rm D}$ =2.3 A, $V_{\rm GS}$ =0 to 2.5 V	-	0.55	-	nC
Gate to drain charge	Q_{gd}		-	0.58	-	
Gate charge total	Qg		-	1.7	-	
Gate plateau voltage	V _{plateau}		-	1.5	-	V
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	0.5	Α
Diode pulse current	I _{S,pulse}	-T _A =25 °C	-	-	9.3	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =2.3 A, T _j =25 °C	-	0.82	1.1	V
Reverse recovery time	t _{rr}	V _R =10 V, I _F =2.3 A,	-	11	-	ns
Reverse recovery charge	Q _{rr}	$di_F/dt = 100 \text{ A/µs}$	-	3.3	-	nC

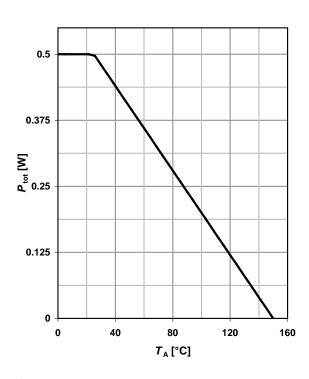


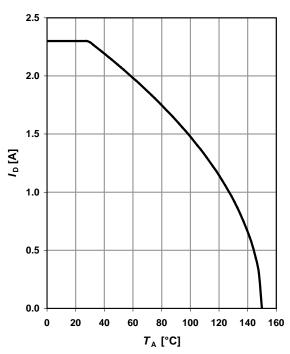
1 Power dissipation

P_{tot} =f(T_A)

2 Drain current

$$I_D = f(T_A); V_{GS} \ge 2.5 \text{ V}$$

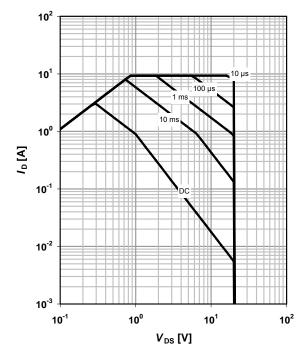




3 Safe operating area

$$I_{\rm D}$$
=f($V_{\rm DS}$); $T_{\rm A}$ =25 °C; D =0

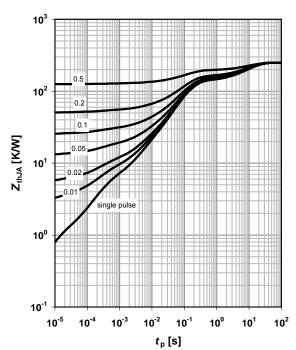
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{\text{thJA}}$$
=f(t_{p})

parameter: $D = t_p/T$

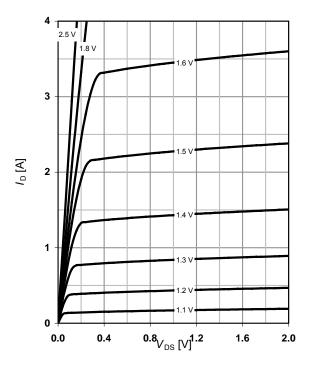




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

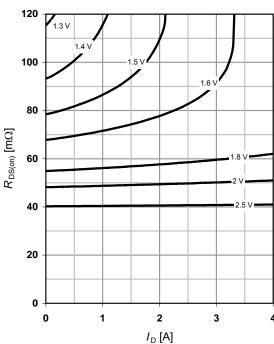
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

parameter: V_{GS}

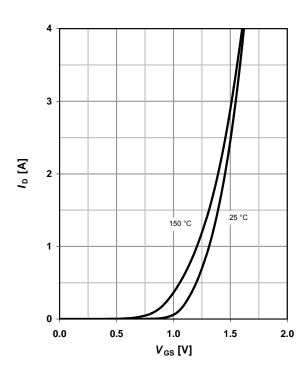


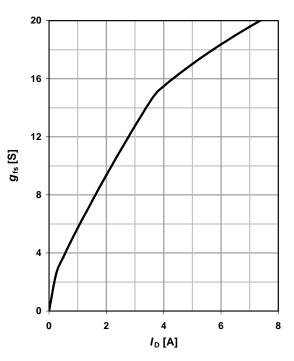
7 Typ. transfer characteristics

 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

8 Typ. forward transconductance

$$g_{fs}$$
=f(I_D); T_j =25 °C

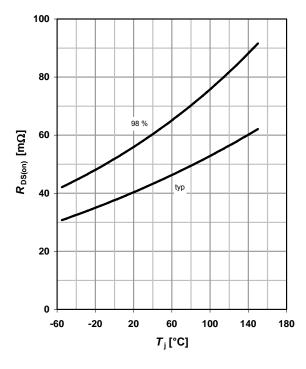






9 Drain-source on-state resistance

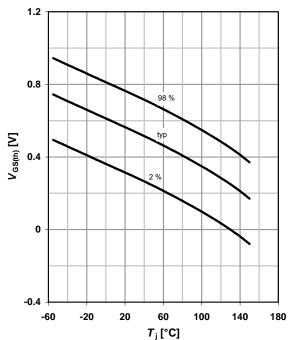
$$R_{DS(on)}$$
=f(T_{j}); I_{D} =2.3 A; V_{GS} =2.5 V



10 Typ. gate threshold voltage

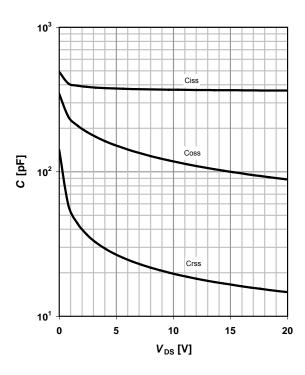
$$V_{GS(th)}$$
=f(T_j); V_{DS} = V_{GS} ; I_D =11 μ A

parameter: I_D



11 Typ. capacitances

 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_j=25$ °C



12 Forward characteristics of reverse diode

$$I_{\text{F}} = f(V_{\text{SD}})$$

parameter: T_{j}

10°1
10°2
10°3
0 0.4 0.8 1.2 1.6

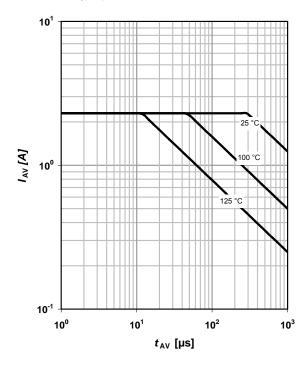
V_{SD}[V]



13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

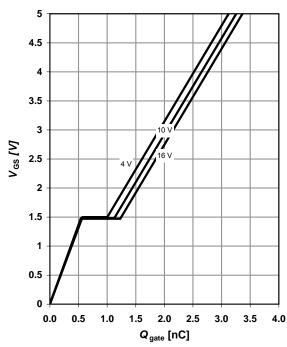
parameter: $T_{j(start)}$



14 Typ. gate charge

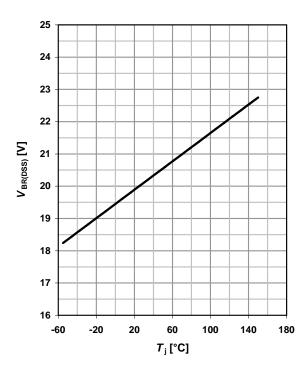
 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =2.3 A pulsed

parameter: $V_{\rm DD}$

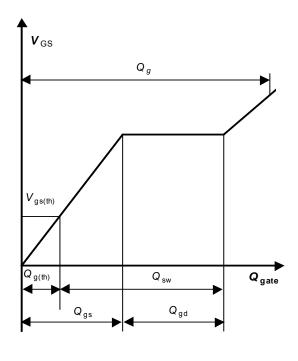


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_i); I_D =250 μ A



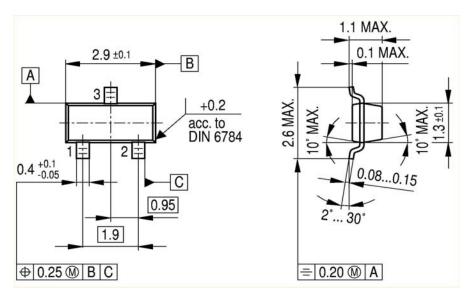
16 Gate charge waveforms





SOT23

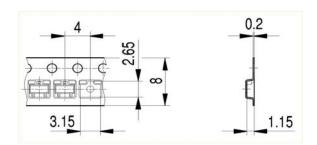
Package Outline:



Footprint:

0.9

Packaging:



Dimensions in mm



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